

ETG052014 23rd May 2014 | Page I of 2

North American EtherCAT Test Center issues first conformance test certificate for an EtherCAT product

The newly-opened North American EtherCAT Test Center (ETC) has reached its first milestone: Watlow's RMZ Temperature Controller is the first EtherCAT device to pass conformance testing in the test lab which is based in Savage, Minnesota (Minneapolis area). During a meeting of the ETG Semiconductor Technical Working Group, the EtherCAT Technology Group (ETG) awarded the official conformance test certificate to Watlow.

The first official certificate for a successfully tested EtherCAT device was issued not long after the new North American EtherCAT Test Center was accredited by the ETG. The North American ETC's first certified product is the new RMZ Multi Loop Temperature Controller from Watlow Electric Manufacturing Company which just recently passed its conformance test. During the official test in an EC the EtherCAT Conformance Test Tool is employed, its use is mandatory for EtherCAT device manufacturers. Additionally, further tests such as interoperability and interface checks are conducted during the test of an EtherCAT device in an official ETC.

The certificate was issued during the 6th meeting of ETG's Semiconductor Technical Working Group hosted by Lam Research, which is located in Silicon Valley in Fremont, California. Florian Häfele, who was onsite as the ETG representative and who presented the certificate to Stan Breitlow, Staff Software Engineer at Watlow, explained: "Awarding the first North American ETC conformance test certificate to Watlow represents a significant kick-off and stresses the importance of the new North American EtherCAT Test Center to the semiconductor and industrial equipment industries. This is also validation to the ETG that it was the right decision to accredit a test lab in North America."

Thanks to regional accessibility, the test lab in Savage, Minnesota will meet the increasing demand for official EtherCAT device tests across North America. The certification of Watlow's temperature controller demonstrates how beneficial the new ETC location is, especially for the test of semiconductor-specific EtherCAT devices. North America is home to many of the world's biggest companies in the semiconductor manufacturing industry and the ETG expects growing demand for EtherCAT conformance tests from this industry well into the future. In addition to the test center in Savage, manufacturers of EtherCAT devices have the option to submit their products for testing at the other official ETCs in Germany, Japan and China. Upon the completion of successful test results at any ETC, the device manufacturers will, of course, receive the official conformance certificate.

Press Release



ETG052014 23rd May 2014 | Page 2 of 2

Press picture



Picture caption:

During a meeting of the ETG Semiconductor Technical Working Group ETG's representative Florian Häfele awarded the first official North American conformance certificate to Stan Breitlow from Watlow.

About EtherCAT Technology Group (ETG):

The EtherCAT Technology Group is an organization in which key user companies from various industries and leading automation suppliers join forces to support, promote and advance the EtherCAT technology. With over 2,700 members from 56 countries, the EtherCAT Technology Group has become the largest fieldbus organization in the world. Founded in November 2003, it is also the fastest growing fieldbus organization.

About EtherCAT®:

EtherCAT is the Industrial Ethernet technology which stands for high-performance, low-cost, ease of use and a flexible topology. It was introduced in 2003 and has been an international IEC standard and a SEMI standard since 2007. EtherCAT is an open technology: anyone can implement or use it.

→ For further information please see: www.ethercat.org

Press contact:

EtherCAT Technology Group

Christiane Heubusch Ostendstraße 196 90482 Nuremberg Germany

Tel.: +49 (0) 9 11 / 5 40 56 226 Fax: +49 (0) 9 11 / 5 40 56 29 c.heubusch@ethercat.org www.ethercat.org/press